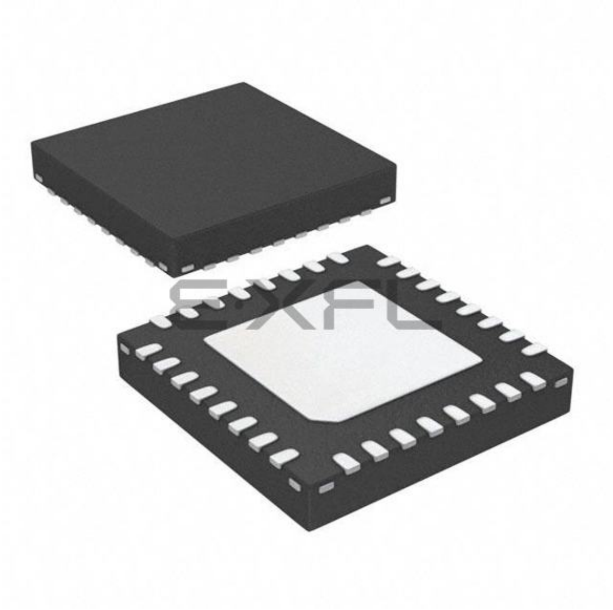
Silicon Labs - EFM8LB11F32E-A-QFN32R Datasheet



What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Discontinued at Digi-Key
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	72MHz
Connectivity	I²C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	29
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 20x14b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	32-UFQFN Exposed Pad
Supplier Device Package	32-QFN (4x4)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8lb11f32e-a-qfn32r

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Voltage DACs	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8LB12F32E-A-QFN32	32	2304	29	20	4	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB12F32E-A-QFP32	32	2304	28	20	4	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB12F32E-A-QFN24	32	2304	20	12	4	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB12F32E-A-QSOP24	32	2304	21	13	4	6	7	Yes	-40 to +105 °C	QSOP24
EFM8LB11F32E-A-QFN32	32	2304	29	20	2	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB11F32E-A-QFP32	32	2304	28	20	2	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB11F32E-A-QFN24	32	2304	20	12	2	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB11F32E-A-QSOP24	32	2304	21	13	2	6	7	Yes	-40 to +105 °C	QSOP24
EFM8LB11F16E-A-QFN32	16	1280	29	20	2	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB11F16E-A-QFP32	16	1280	28	20	2	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB11F16E-A-QFN24	16	1280	20	12	2	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB11F16E-A-QSOP24	16	1280	21	13	2	6	7	Yes	-40 to +105 °C	QSOP24
EFM8LB10F16E-A-QFN32	16	1280	29	20	0	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB10F16E-A-QFP32	16	1280	28	20	0	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB10F16E-A-QFN24	16	1280	20	12	0	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB10F16E-A-QSOP24	16	1280	21	13	0	6	7	Yes	-40 to +105 °C	QSOP24

Timers (Timer 0, Timer 1, Timer 2, Timer 3, Timer 4, and Timer 5)

Several counter/timers are included in the device: two are 16-bit counter/timers compatible with those found in the standard 8051, and the rest are 16-bit auto-reload timers for timing peripherals or for general purpose use. These timers can be used to measure time intervals, count external events and generate periodic interrupt requests. Timer 0 and Timer 1 are nearly identical and have four primary modes of operation. The other timers offer both 16-bit and split 8-bit timer functionality with auto-reload and capture capabilities.

Timer 0 and Timer 1 include the following features:

- Standard 8051 timers, supporting backwards-compatibility with firmware and hardware.
- Clock sources include SYSCLK, SYSCLK divided by 12, 4, or 48, the External Clock divided by 8, or an external pin.
- 8-bit auto-reload counter/timer mode
- 13-bit counter/timer mode
- 16-bit counter/timer mode
- Dual 8-bit counter/timer mode (Timer 0)

Timer 2, Timer 3, Timer 4, and Timer 5 are 16-bit timers including the following features:

- Clock sources for all timers include SYSCLK, SYSCLK divided by 12, or the External Clock divided by 8
- LFOSC0 divided by 8 may be used to clock Timer 3 and Timer 4 in active or suspend/snooze power modes
- Timer 4 is a low-power wake source, and can be chained together with Timer 3
- 16-bit auto-reload timer mode
- Dual 8-bit auto-reload timer mode
- External pin capture
- LFOSC0 capture
- Comparator 0 capture
- Configurable Logic output capture

Watchdog Timer (WDT0)

The device includes a programmable watchdog timer (WDT) running off the low-frequency oscillator. A WDT overflow forces the MCU into the reset state. To prevent the reset, the WDT must be restarted by application software before overflow. If the system experiences a software or hardware malfunction preventing the software from restarting the WDT, the WDT overflows and causes a reset. Following a reset, the WDT is automatically enabled and running with the default maximum time interval. If needed, the WDT can be disabled by system software or locked on to prevent accidental disabling. Once locked, the WDT cannot be disabled until the next system reset. The state of the RST pin is unaffected by this reset.

The Watchdog Timer has the following features:

- Programmable timeout interval
- Runs from the low-frequency oscillator
- Lock-out feature to prevent any modification until a system reset

3.6 Communications and Other Digital Peripherals

Universal Asynchronous Receiver/Transmitter (UART0)

UART0 is an asynchronous, full duplex serial port offering modes 1 and 3 of the standard 8051 UART. Enhanced baud rate support allows a wide range of clock sources to generate standard baud rates. Received data buffering allows UART0 to start reception of a second incoming data byte before software has finished reading the previous data byte.

The UART module provides the following features:

- Asynchronous transmissions and receptions
- Baud rates up to SYSCLK/2 (transmit) or SYSCLK/8 (receive)
- 8- or 9-bit data
- Automatic start and stop generation
- Single-byte buffer on transmit and receive

4.1.12 DACs

Table 4.12. DACs

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}			12		Bits
Throughput Rate	f_S		—	—	200	ksps
Integral Nonlinearity	INL		TBD	±0.5	TBD	LSB
Differential Nonlinearity	DNL		TBD	±5	TBD	LSB
Output Noise	VREF = 2.4 V f_S = 0.1 Hz to 300 kHz		—	110	—	μV_{RMS}
Slew Rate	SLEW		—	±1	—	V/µs
Output Settling Time to 1 LSB	t_{SETTLE}	V_{OUT} change between 25% and 75% Full Scale	—	2.6	5	µs
Power-on Time	t_{PWR}		—	—	10	µs
Voltage Reference Range	V_{REF}		1.15	—	V_{DD}	V
Power Supply Rejection Ratio	PSRR	DC, V_{OUT} = 50% Full Scale	—	110	—	dB
		1 kHz, V_{OUT} = 50% Full Scale	—	60	—	dB
Total Harmonic Distortion	THD	V_{OUT} = 10 kHz sine wave, 10% to 90%	60	—	—	dB
Offset Error	E_{OFF}	VREF = 2.4 V	TBD	±0.5	TBD	LSB
Offset Temperature Coefficient	TC_{OFF}		—	TBD	—	ppm/°C
Full-Scale Error	E_{FS}	VREF = 2.4 V	TBD	±5	TBD	LSB
Full-Scale Error Tempco	TC_{FS}		—	TBD	—	ppm/°C
External Load Impedance	R_{LOAD}		2	—	—	kΩ
External Load Capacitance	C_{LOAD}		TBD	—	100	pF
Load Regulation		V_{OUT} = 50% Full Scale I_{OUT} = -2 to 2 mA	—	100	TBD	µV/mA

4.1.13 Comparators

Table 4.13. Comparators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Response Time, CPMD = 00 (Highest Speed)	t_{RESP0}	+100 mV Differential	—	100	—	ns
		-100 mV Differential	—	150	—	ns
Response Time, CPMD = 11 (Lowest Power)	t_{RESP3}	+100 mV Differential	—	1.5	—	µs
		-100 mV Differential	—	3.5	—	µs
Positive Hysteresis Mode 0 (CPMD = 00)	HYS_{CP+}	CPHYP = 00	—	0.4	—	mV
		CPHYP = 01	—	8	—	mV
		CPHYP = 10	—	16	—	mV
		CPHYP = 11	—	32	—	mV
Negative Hysteresis Mode 0 (CPMD = 00)	HYS_{CP-}	CPHYN = 00	—	-0.4	—	mV
		CPHYN = 01	—	-8	—	mV
		CPHYN = 10	—	-16	—	mV
		CPHYN = 11	—	-32	—	mV
Positive Hysteresis Mode 1 (CPMD = 01)	HYS_{CP+}	CPHYP = 00	—	0.5	—	mV
		CPHYP = 01	—	6	—	mV
		CPHYP = 10	—	12	—	mV
		CPHYP = 11	—	24	—	mV
Negative Hysteresis Mode 1 (CPMD = 01)	HYS_{CP-}	CPHYN = 00	—	-0.5	—	mV
		CPHYN = 01	—	-6	—	mV
		CPHYN = 10	—	-12	—	mV
		CPHYN = 11	—	-24	—	mV
Positive Hysteresis Mode 2 (CPMD = 10)	HYS_{CP+}	CPHYP = 00	—	0.7	—	mV
		CPHYP = 01	—	4.5	—	mV
		CPHYP = 10	—	9	—	mV
		CPHYP = 11	—	18	—	mV
Negative Hysteresis Mode 2 (CPMD = 10)	HYS_{CP-}	CPHYN = 00	—	-0.6	—	mV
		CPHYN = 01	—	-4.5	—	mV
		CPHYN = 10	—	-9	—	mV
		CPHYN = 11	—	-18	—	mV
Positive Hysteresis Mode 3 (CPMD = 11)	HYS_{CP+}	CPHYP = 00	—	1.5	—	mV
		CPHYP = 01	—	4	—	mV
		CPHYP = 10	—	8	—	mV
		CPHYP = 11	—	16	—	mV

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Negative Hysteresis Mode 3 (CPMD = 11)	HYS_{CP-}	CPHYN = 00	—	-1.5	—	mV
		CPHYN = 01	—	-4	—	mV
		CPHYN = 10	—	-8	—	mV
		CPHYN = 11	—	-16	—	mV
Input Range (CP+ or CP-)	V_{IN}		-0.25	—	V_{IO}+0.25	V
Input Pin Capacitance	C_{CP}		—	7.5	—	pF
Internal Reference DAC Resolution	N_{bits}			6		bits
Common-Mode Rejection Ratio	$CMRR_{CP}$		—	70	—	dB
Power Supply Rejection Ratio	$PSRR_{CP}$		—	72	—	dB
Input Offset Voltage	V_{OFF}	T_A = 25 °C	-10	0	10	mV
Input Offset Tempco	TC_{OFF}		—	3.5	—	µV/°

4.1.14 Configurable Logic

Table 4.14. Configurable Logic

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Propagation Delay	t_{DLY}	Through single CLU	TBD	—	TBD	ns
Clocking Frequency	F_{CLK}	1 or 2 CLUs Cascaded	—	—	73.5	MHz
		3 or 4 CLUs Cascaded	—	—	36.75	MHz

4.1.15 Port I/O

Table 4.15. Port I/O

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output High Voltage (High Drive)	V_{OH}	I_{OH} = -7 mA, $V_{IO} \geq 3.0$ V	V_{IO} - 0.7	—	—	V
		I_{OH} = -3.3 mA, 2.2 V ≤ V_{IO} < 3.0 V I_{OH} = -1.8 mA, 1.71 V ≤ V_{IO} < 2.2 V	V_{IO} x 0.8	—	—	V
Output Low Voltage (High Drive)	V_{OL}	I_{OL} = 13.5 mA, $V_{IO} \geq 3.0$ V	—	—	0.6	V
		I_{OL} = 7 mA, 2.2 V ≤ V_{IO} < 3.0 V I_{OL} = 3.6 mA, 1.71 V ≤ V_{IO} < 2.2 V	—	—	V_{IO} x 0.2	V
Output High Voltage (Low Drive)	V_{OH}	I_{OH} = -4.75 mA, $V_{IO} \geq 3.0$ V	V_{IO} - 0.7	—	—	V
		I_{OH} = -2.25 mA, 2.2 V ≤ V_{IO} < 3.0 V I_{OH} = -1.2 mA, 1.71 V ≤ V_{IO} < 2.2 V	V_{IO} x 0.8	—	—	V
Output Low Voltage (Low Drive)	V_{OL}	I_{OL} = 6.5 mA, $V_{IO} \geq 3.0$ V	—	—	0.6	V
		I_{OL} = 3.5 mA, 2.2 V ≤ V_{IO} < 3.0 V I_{OL} = 1.8 mA, 1.71 V ≤ V_{IO} < 2.2 V	—	—	V_{IO} x 0.2	V
Input High Voltage	V_{IH}		0.7 x V_{IO}	—	—	V
Input Low Voltage	V_{IL}		—	—	0.3 x V_{IO}	V
Pin Capacitance	C_{IO}		—	7	—	pF
Weak Pull-Up Current (V_{IN} = 0 V)	I_{PU}	V_{DD} = 3.6	-30	-20	-10	μA
Input Leakage (Pullups off or Analog)	I_{LK}	GND < V_{IN} < V_{IO}	TBD	—	TBD	μA
Input Leakage Current with V_{IN} above V_{IO}	I_{LK}	V_{IO} < V_{IN} < V_{IO}+2.5 V Any pin except P3.0, P3.1, P3.2, or P3.3	0	5	150	μA

4.2 Thermal Conditions

Table 4.16. Thermal Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance	θ_{JA}	QFN24 Packages	—	TBD	—	°C/W
		QFN32 Packages	—	TBD	—	°C/W
		QFP32 Packages	—	80	—	°C/W
		QSOP24 Packages	—	65	—	°C/W

Note:

1. Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.

4.3 Absolute Maximum Ratings

Stresses above those listed in Table 4.17 Absolute Maximum Ratings on page 27 may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at http://www.silabs.com/support/quality/pages/default.aspx.

Table 4.17. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		-55	125	°C
Storage Temperature	T_{STG}		-65	150	°C
Voltage on VDD	V_{DD}		GND-0.3	4.2	V
Voltage on VIO[2]	V_{IO}		GND-0.3	V_{DD}+0.3	V
Voltage on I/O pins or RSTb, excluding P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	V_{IN}	V_{IO} > TBD V	GND-0.3	TBD	V
		V_{IO} < TBD V	GND-0.3	TBD	V
Voltage on P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	V_{IN}		GND-0.3	V_{DD}+0.3	V
Total Current Sunk into Supply Pin	I_{VDD}		—	400	mA
Total Current Sourced out of Ground Pin	I_{GND}		400	—	mA
Current Sourced or Sunk by any I/O Pin or RSTb	I_{IO}		-100	100	mA

Note:

1. Exposure to maximum rating conditions for extended periods may affect device reliability.
2. In certain package configurations, the VIO and VDD supplies are bonded to the same pin.

5.2 Debug

The diagram below shows a typical connection diagram for the debug connections pins. The pin sharing resistors are only required if the functionality on the C2D (a GPIO pin) and the C2CK (RSTb) is routed to external circuitry. For example, if the RSTb pin is connected to an external switch with debouncing filter or if the GPIO sharing with the C2D pin is connected to an external circuit, the pin sharing resistors and connections to the debug adapter must be placed on the hardware. Otherwise, these components and connections can be omitted.

For more information on debug connections, see the example schematics and information available in AN127: "Pin Sharing Techniques for the C2 Interface." Application notes can be found on the Silicon Labs website (http://www.silabs.com/8bit-appnotes) or in Simplicity Studio.

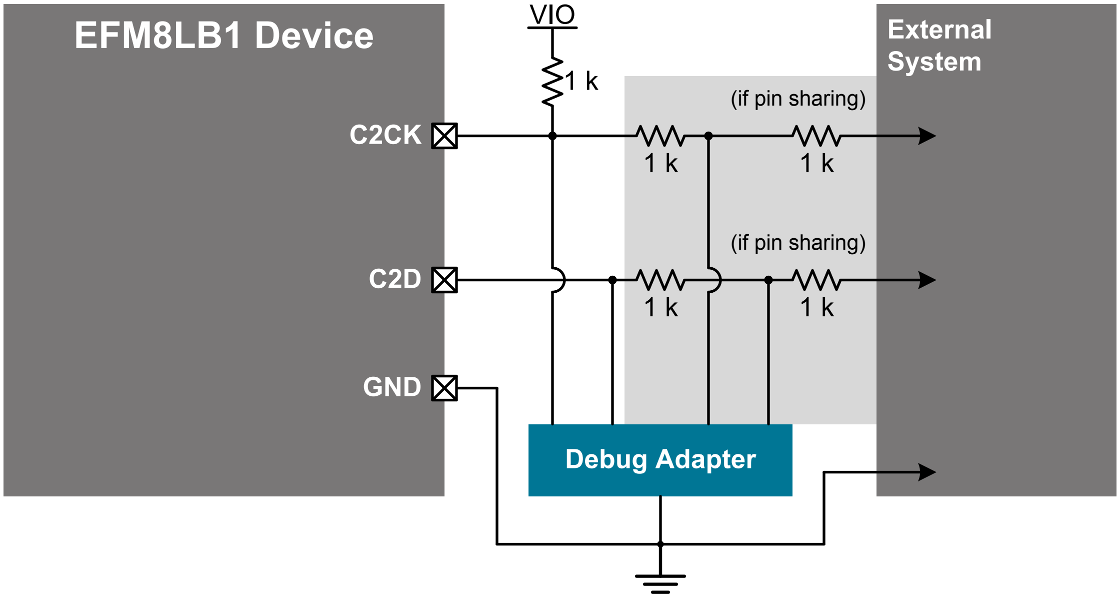


Figure 5.2. Debug Connection Diagram

5.3 Other Connections

Other components or connections may be required to meet the system-level requirements. Application Note AN203: "8-bit MCU Printed Circuit Board Design Notes" contains detailed information on these connections. Application Notes can be accessed on the Silicon Labs website (www.silabs.com/8bit-appnotes).

6. Pin Definitions

6.1 EFM8LB1x-QFN32 Pin Definitions

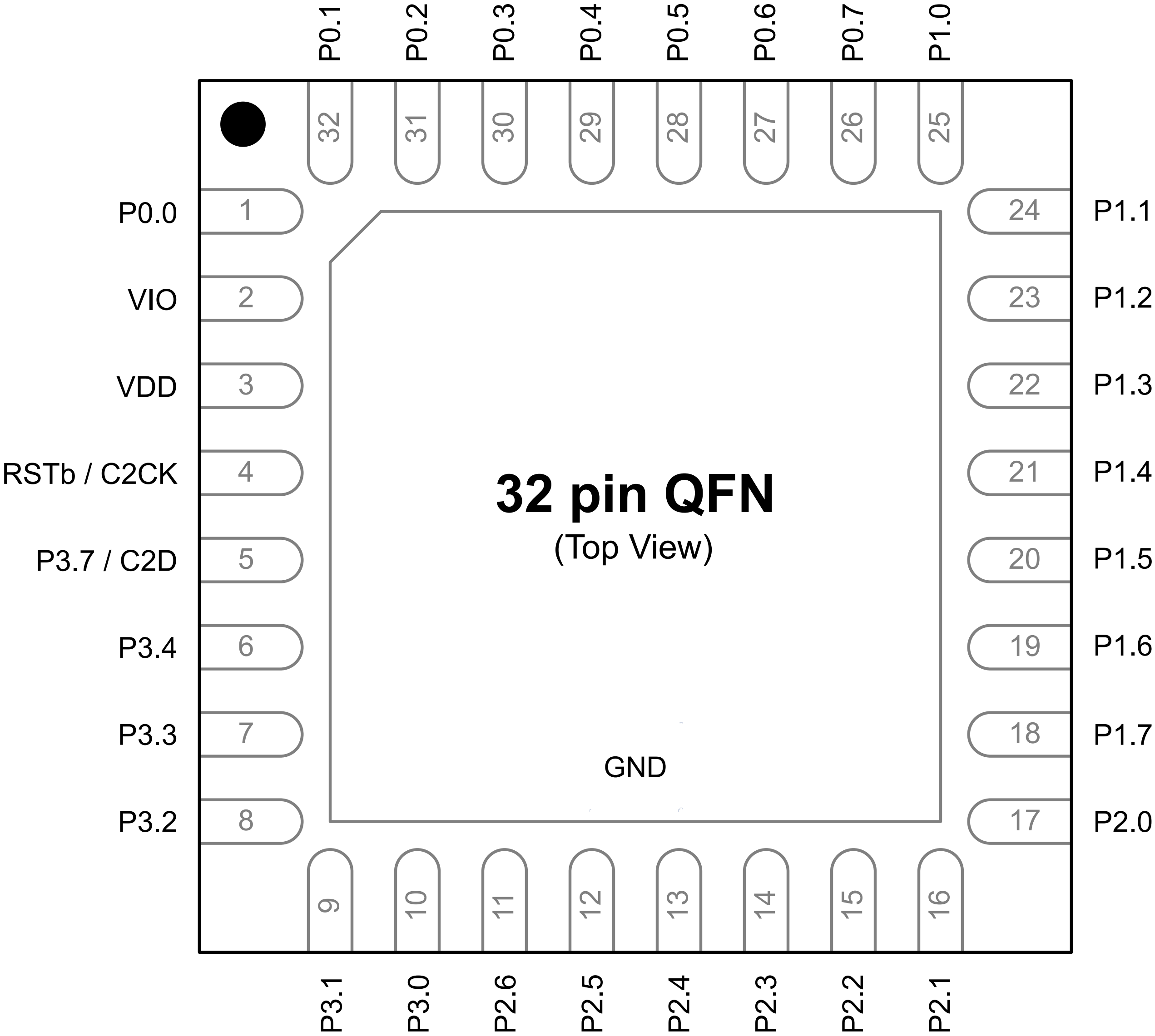


Figure 6.1. EFM8LB1x-QFN32 Pinout

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
22	P1.3	Multifunction I/O	Yes	P1MAT.3 CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	ADC0.9
23	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12 CLU3B.13	ADC0.8 CMP0P.8 CMP0N.8
24	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.12	ADC0.7 CMP0P.7 CMP0N.7
25	P1.0	Multifunction I/O	Yes	P1MAT.0 CLU1OUT CLU0A.12 CLU1A.10 CLU2A.10	ADC0.6 CMP0P.6 CMP0N.6 CMP1P.1 CMP1N.1
26	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7 CLU0B.11 CLU1B.9 CLU3A.11	ADC0.5 CMP0P.5 CMP0N.5 CMP1P.0 CMP1N.0
27	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6 CLU0A.11 CLU1B.8 CLU3A.10	ADC0.4 CMP0P.4 CMP0N.4

6.2 EFM8LB1x-QFP32 Pin Definitions

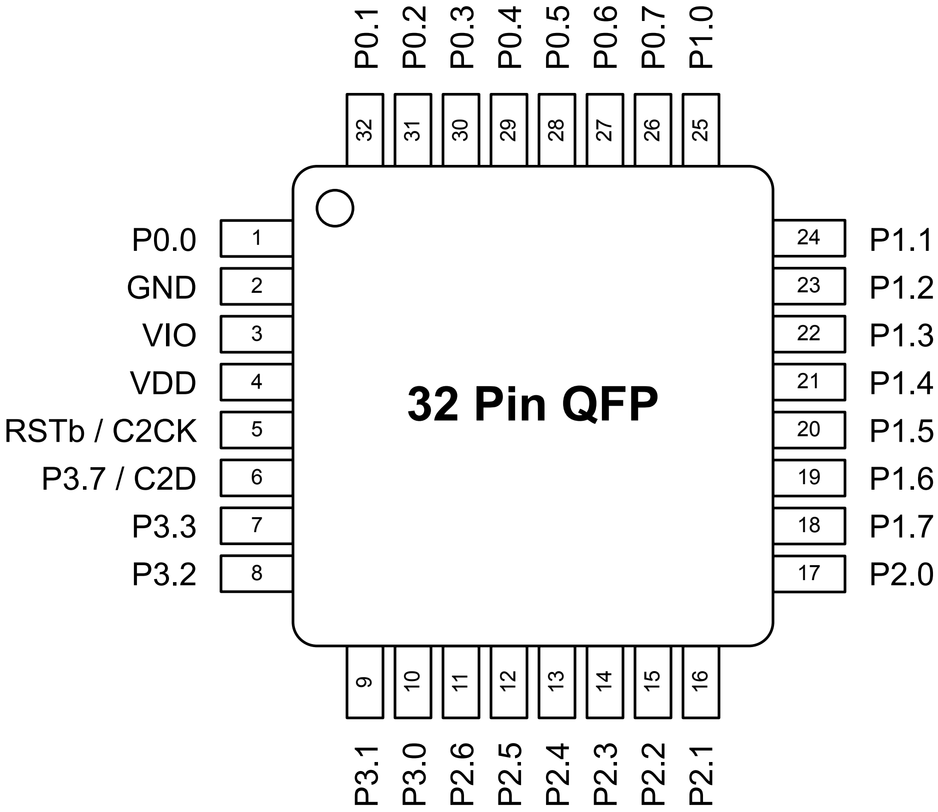


Figure 6.2. EFM8LB1x-QFP32 Pinout

Table 6.2. Pin Definitions for EFM8LB1x-QFP32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
2	GND	Ground			
3	VIO	I/O Supply Power Input			
4	VDD	Supply Power Input			
5	RSTb / C2CK	Active-low Reset / C2 Debug Clock			

6.3 EFM8LB1x-QFN24 Pin Definitions

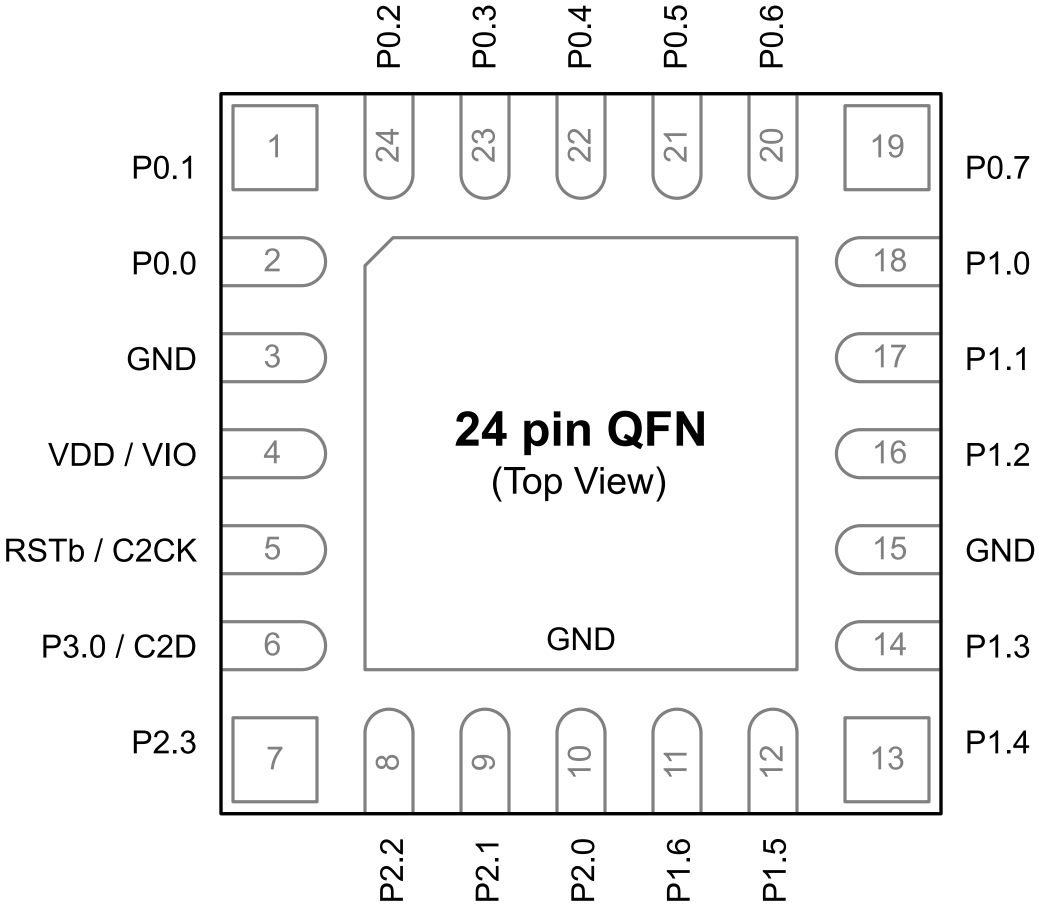


Figure 6.3. EFM8LB1x-QFN24 Pinout

Table 6.3. Pin Definitions for EFM8LB1x-QFN24

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1 CLU0B.8 CLU2A.9 CLU3B.9	ADC0.0 CMP0P.0 CMP0N.0 AGND

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
2	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
3	GND	Ground			
4	VDD / VIO	Supply Power Input			
5	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
6	P3.0 / C2D	Multifunction I/O / C2 Debug Data			
7	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	DAC3
8	P2.2	Multifunction I/O	Yes	P2MAT.2 CLU1A.15 CLU2B.14 CLU3A.14	DAC2
9	P2.1	Multifunction I/O	Yes	P2MAT.1 CLU1B.14 CLU2A.15 CLU3B.15	DAC1
10	P2.0	Multifunction I/O	Yes	P2MAT.0 CLU1A.14 CLU2A.14 CLU3B.14	DAC0
11	P1.6	Multifunction I/O	Yes	P1MAT.6 CLU3OUT CLU0A.15 CLU1B.12 CLU2A.12	ADC0.11 CMP1P.5 CMP1N.5

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
19	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7 CLU1OUT CLU0B.11 CLU1B.9 CLU3A.11	ADC0.5 CMP0P.5 CMP0N.5 CMP1P.1 CMP1N.1
20	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6 CLU0A.11 CLU1B.8 CLU3A.10	ADC0.4 CMP0P.4 CMP0N.4 CMP1P.0 CMP1N.0
21	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX CLU0B.10 CLU1A.9	ADC0.3 CMP0P.3 CMP0N.3
22	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4 UART0_TX CLU0A.10 CLU1A.8	ADC0.2 CMP0P.2 CMP0N.2
23	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3 CLU0B.9 CLU2B.10 CLU3A.9	XTAL2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
24	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4 UART0_TX CLU0A.10 CLU1A.8	ADC0.2 CMP0P.2 CMP0N.2

Dimension	Min	Typ	Max
Note: 1. All dimensions shown are in millimeters (mm) unless otherwise noted. 2. Dimensioning and Tolerancing per ANSI Y14.5M-1994. 3. This drawing conforms to JEDEC Solid State Outline MO-220. 4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.			

Dimension	Min	Typ	Max
aaa		0.20	
bbb		0.20	
ccc		0.10	
ddd		0.20	
theta	0°	3.5°	7°

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MS-026.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

9.2 QFN24 PCB Land Pattern

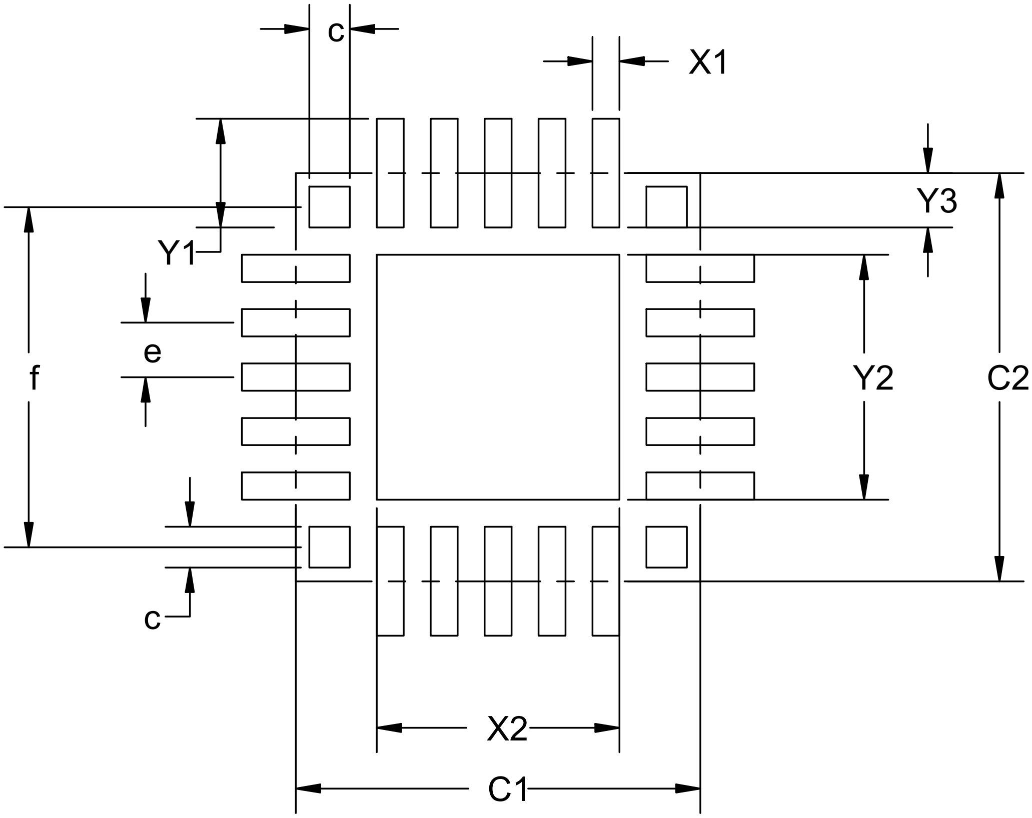


Figure 9.2. QFN24 PCB Land Pattern Drawing

Table 9.2. QFN24 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	3.00	
C2	3.00	
e	0.4 REF	
X1	0.20	
X2	1.80	
Y1	0.80	
Y2	1.80	
Y3	0.4	
f	2.50 REF	
c	0.25	0.35

11. Revision History

11.1 Revision 0.1

Initial release.

11.2 Revision 0.2

Added information on the bootloader to 3.10 Bootloader.

Updated some characterization TBD values.

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